

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	09/867,644	JUANG ET AL.	
Examiner		Art Unit	Page 1 of 1
A. Sefer		2826	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-3,916,071	10-1975	Kinnebrew et al	428/376
	B	US-20020075131	06-2002	Coates et al	338/308
	C	US-4,788,523	11-1988	Robins	338/309
	D	US-4677413	06-1987	Zandman et al	338/7
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 8-22903	01-1996	Japan	Shimada	
	O	JP 2000-173801	06-2000	Japan	Sone et al	
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages
	U	Thomas et al. "Ti-Cu-Ni-Au (TCNA) compatibility with resistor and bilevel crossover circuit processing" (J. Vac. Sci. Technol., Vol. 13, No. 1, Jan/Feb. 1976).
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.